

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/654,228	HAYEK ET AL.	
Examiner Nathan W. Schlientz		Art Unit 1616	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
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FOREIGN PATENT DOCUMENTS

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	N	JP 57192318 A	11-1982	Japan	KOMINATO et al.	
	O					
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NON-PATENT DOCUMENTS

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